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## Understanding [Embedded - CPLDs \(Complex Programmable Logic Devices\)](#)

Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixed-function ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

## Applications of Embedded - CPLDs

### Details

Product Status	Obsolete
Programmable Type	EE PLD
Delay Time tpd(1) Max	25 ns
Voltage Supply - Internal	4.75V ~ 5.25V
Number of Logic Elements/Blocks	-
Number of Macrocells	8
Number of Gates	-
Number of I/O	-
Operating Temperature	0°C ~ 75°C (TA)
Mounting Type	Through Hole
Package / Case	24-DIP (0.300", 7.62mm)
Supplier Device Package	24-PDIP
Purchase URL	<a href="https://www.e-xfl.com/product-detail/lattice-semiconductor/gal20v8b-25qpn">https://www.e-xfl.com/product-detail/lattice-semiconductor/gal20v8b-25qpn</a>

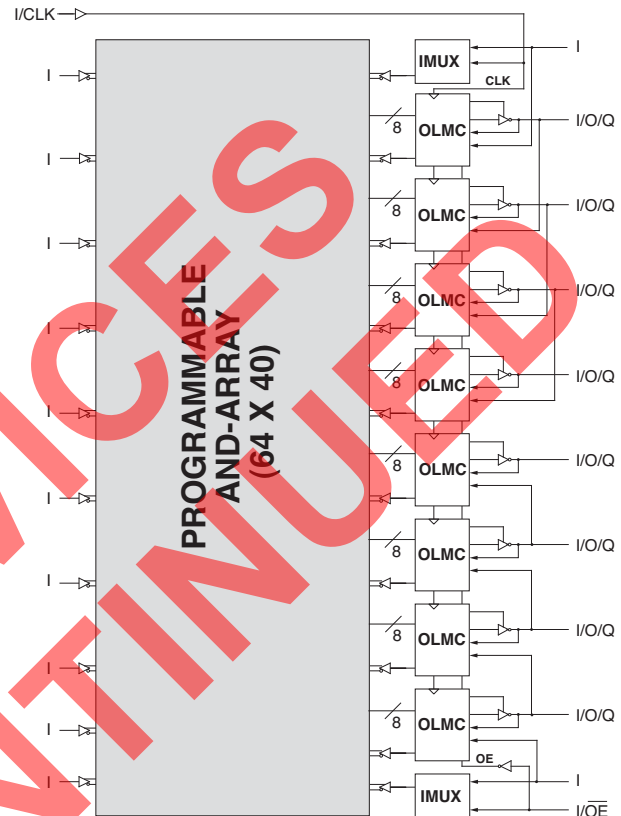


Product Line	Ordering Part Number	Product Status	Reference PCN
<b>GAL20V8B (Cont'd)</b>	GAL20V8B-25QJ	<b>Discontinued</b>	<a href="#">PCN#13-10</a>
	GAL20V8B-25QJN		
	GAL20V8B-20QJI		<a href="#">PCN#09-10</a>
	GAL20V8B-20QJNI		
	GAL20V8B-25QJI		<a href="#">PCN#13-10</a>
	GAL20V8B-25QJNI		
<b>GAL20V8C</b>	GAL20V8C-5LJ		<a href="#">PCN#06-07</a>
	GAL20V8C-5LJN		
	GAL20V8C-7LJ		<a href="#">PCN#13-10</a>
	GAL20V8C-7LJN		
	GAL20V8C-10LJ		
	GAL20V8C-10LJN		
	GAL20V8C-10LJI		
	GAL20V8C-10LJNI		

## Features

- **HIGH PERFORMANCE E<sup>2</sup>CMOS® TECHNOLOGY**
  - 5 ns Maximum Propagation Delay
  - Fmax = 166 MHz
  - 4 ns Maximum from Clock Input to Data Output
  - UltraMOS® Advanced CMOS Technology
- **50% to 75% REDUCTION IN POWER FROM BIPOLAR**
  - 75mA Typ Icc on Low Power Device
  - 45mA Typ Icc on Quarter Power Device
- **ACTIVE PULL-UPS ON ALL PINS**
- **E<sup>2</sup> CELL TECHNOLOGY**
  - Reconfigurable Logic
  - Reprogrammable Cells
  - 100% Tested/100% Yields
  - High Speed Electrical Erasure (<100ms)
  - 20 Year Data Retention
- **EIGHT OUTPUT LOGIC MACROCELLS**
  - Maximum Flexibility for Complex Logic Designs
  - Programmable Output Polarity
  - Also Emulates 24-pin PAL® Devices with Full Function/  
Fuse Map/Parametric Compatibility
- **PRELOAD AND POWER-ON RESET OF ALL REGISTERS**
  - 100% Functional Testability
- **APPLICATIONS INCLUDE:**
  - DMA Control
  - State Machine Control
  - High Speed Graphics Processing
  - Standard Logic Speed Upgrade
- **ELECTRONIC SIGNATURE FOR IDENTIFICATION**
- **LEAD-FREE PACKAGE OPTIONS**

## Functional Block Diagram



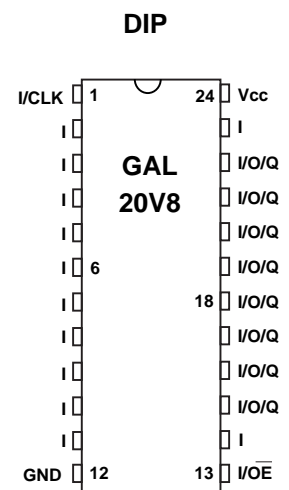
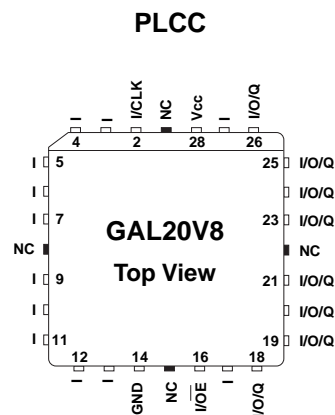
## Description

The GAL20V8C, at 5ns maximum propagation delay time, combines a high performance CMOS process with Electrically Erasable (E<sup>2</sup>) floating gate technology to provide the highest speed performance available in the PLD market. High speed erase times (<100ms) allow the devices to be reprogrammed quickly and efficiently.

The generic architecture provides maximum design flexibility by allowing the Output Logic Macrocell (OLMC) to be configured by the user. An important subset of the many architecture configurations possible with the GAL20V8 are the PAL architectures listed in the table of the macrocell description section. GAL20V8 devices are capable of emulating any of these PAL architectures with full function/fuse map/parametric compatibility.

Unique test circuitry and reprogrammable cells allow complete AC, DC, and functional testing during manufacture. As a result, Lattice Semiconductor delivers 100% field programmability and functionality of all GAL products. In addition, 100 erase/write cycles and data retention in excess of 20 years are specified.

## Pin Configuration



## GAL20V8 Ordering Information

### Conventional Packaging Commercial Grade Specifications

Tpd (ns)	Tsu (ns)	Tco (ns)	Icc (mA)	Ordering #	Package
5	3	4	115	GAL20V8C-5LJ <sup>1</sup>	28-Lead PLCC
7.5	7	5	115	GAL20V8C-7LJ	28-Lead PLCC
			115	GAL20V8B-7LP <sup>1</sup>	24-Pin Plastic DIP
10	10	7	115	GAL20V8C-10LJ	28-Lead PLCC
			115	GAL20V8B-10LP	24-Pin Plastic DIP
15	12	10	55	GAL20V8B-15QP	24-Pin Plastic DIP
			55	GAL20V8B-15QJ	28-Lead PLCC
			90	GAL20V8B-15LP	24-Pin Plastic DIP
			90	GAL20V8B-15LJ	28-Lead PLCC
25	15	12	55	GAL20V8B-25QP	24-Pin Plastic DIP
			55	GAL20V8B-25QJ	28-Lead PLCC
			90	GAL20V8B-25LP	24-Pin Plastic DIP
			90	GAL20V8B-25LJ	28-Lead PLCC

### Industrial Grade Specifications

Tpd (ns)	Tsu (ns)	Tco (ns)	Icc (mA)	Ordering #	Package
10	10	7	130	GAL20V8C-10LJI	28-Lead PLCC
			130	GAL20V8B-10LPI <sup>1</sup>	24-Pin Plastic DIP
			130	GAL20V8B-10LJI	28-Lead PLCC
15	12	10	130	GAL20V8B-15LPI	24-Pin Plastic DIP
			130	GAL20V8B-15LJI	28-Lead PLCC
20	13	11	65	GAL20V8B-20QPI	24-Pin Plastic DIP
			65	GAL20V8B-20QJI	28-Lead PLCC
25	15	12	65	GAL20V8B-25QPI	24-Pin Plastic DIP
			65	GAL20V8B-25QJI	28-Lead PLCC
			130	GAL20V8B-25LPI	24-Pin Plastic DIP
			130	GAL20V8B-25LJI	28-Lead PLCC

1. Discontinued per PCN #06-07. Contact Rochester Electronics for available inventory.

## Output Logic Macrocell (OLMC)

The following discussion pertains to configuring the output logic macrocell. It should be noted that actual implementation is accomplished by development software/hardware and is completely transparent to the user.

There are three global OLMC configuration modes possible: **simple**, **complex**, and **registered**. Details of each of these modes is illustrated in the following pages. Two global bits, SYN and AC0, control the mode configuration for all macrocells. The XOR bit of each macrocell controls the polarity of the output in any of the three modes, while the AC1 bit of each of the macrocells controls the input/output configuration. These two global and 16 individual architecture bits define all possible configurations in a GAL20V8. The information given on these architecture bits is only to give a better understanding of the device. Compiler software will transparently set these architecture bits from the pin definitions, so the user should not need to directly manipulate these architecture bits.

The following is a list of the PAL architectures that the GAL20V8 can emulate. It also shows the OLMC mode under which the devices emulate the PAL architecture.

PAL Architectures Emulated by GAL20V8	GAL20V8 Global OLMC Mode
20R8 20R6 20R4 20RP8 20RP6 20RP4	Registered Registered Registered Registered Registered Registered
20L8 20H8 20P8	Complex Complex Complex
14L8 16L6 18L4 20L2 14H8 16H6 18H4 20H2 14P8 16P6 18P4 20P2	Simple Simple Simple Simple Simple Simple Simple Simple Simple Simple Simple Simple Simple

## Compiler Support for OLMC

Software compilers support the three different global OLMC modes as different device types. These device types are listed in the table below. Most compilers have the ability to automatically select the device type, generally based on the register usage and output enable (OE) usage. Register usage on the device forces the software to choose the registered mode. All combinatorial outputs with OE controlled by the product term will force the software to choose the complex mode. The software will choose the simple mode only when all outputs are dedicated combinatorial without OE control. The different device types listed in the table can be used to override the automatic device selection by the software. For further details, refer to the compiler software manuals.

When using compiler software to configure the device, the user must pay special attention to the following restrictions in each mode. In **registered mode** pin 1 and pin 13 (DIP pinout) are permanently

configured as clock and output enable, respectively. These pins cannot be configured as dedicated inputs in the registered mode.

In **complex mode** pin 1 and pin 13 become dedicated inputs and use the feedback paths of pin 22 and pin 15 respectively. Because of this feedback path usage, pin 22 and pin 15 do not have the feedback option in this mode.

In **simple mode** all feedback paths of the output pins are routed via the adjacent pins. In doing so, the two inner most pins ( pins 18 and 19) will not have the feedback option as these pins are always configured as dedicated combinatorial output.

	Registered	Complex	Simple	Auto Mode Select
ABEL	P20V8R	P20V8C	P20V8AS	P20V8
CUPL	G20V8MS	G20V8MA	G20V8AS	G20V8
LOG/IC	GAL20V8_R	GAL20V8_C7	GAL20V8_C8	GAL20V8
OrCAD-PLD	"Registered" <sup>1</sup>	"Complex" <sup>1</sup>	"Simple" <sup>1</sup>	GAL20V8A
PLDesigner	P20V8R <sup>2</sup>	P20V8C <sup>2</sup>	P20V8C <sup>2</sup>	P20V8A
TANGO-PLD	G20V8R	G20V8C	G20V8AS <sup>3</sup>	G20V8

1) Used with **Configuration** keyword.

2) Prior to Version 2.0 support.

3) Supported on Version 1.20 or later.

## Registered Mode

In the Registered mode, macrocells are configured as dedicated registered outputs or as I/O functions.

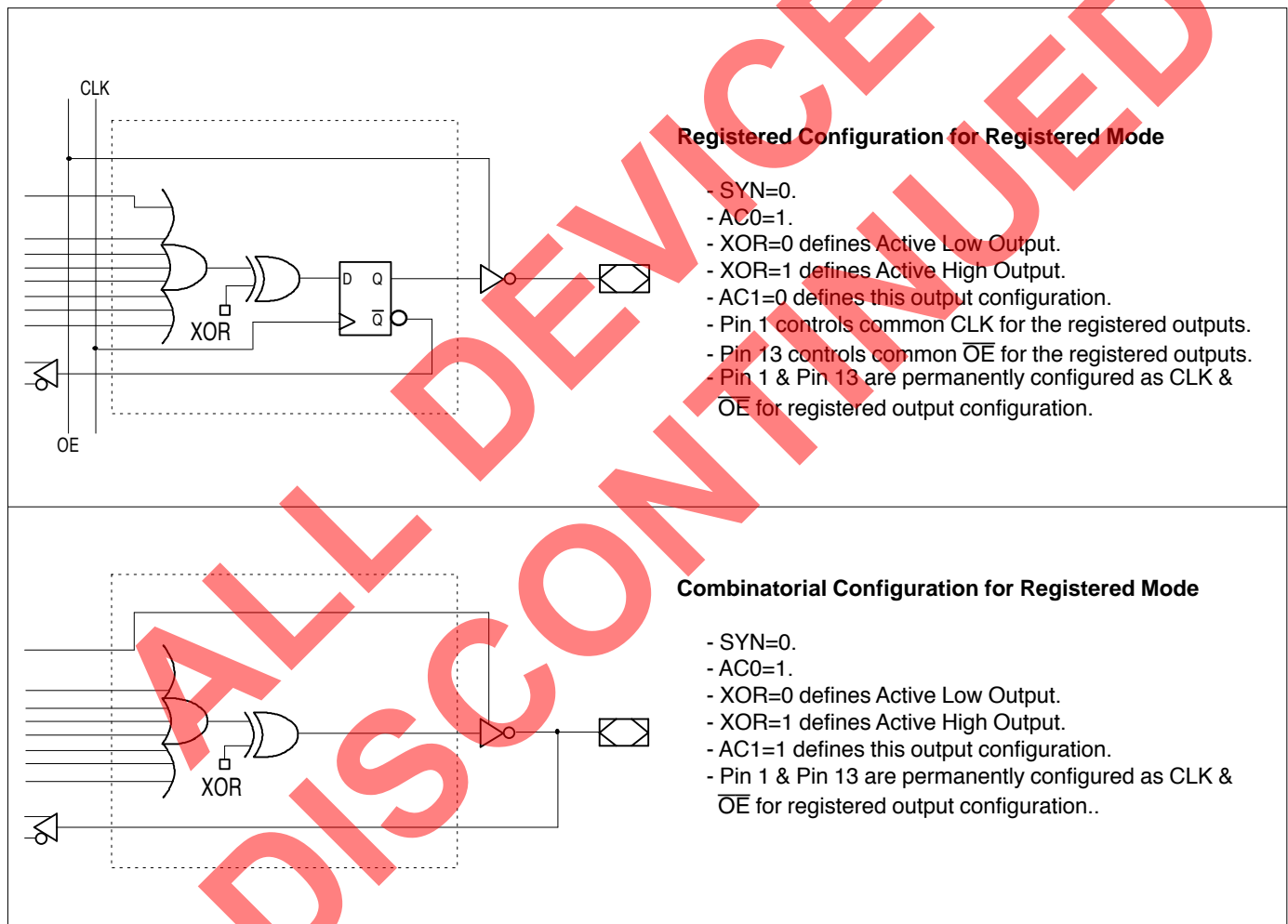
Architecture configurations available in this mode are similar to the common 20R8 and 20RP4 devices with various permutations of polarity, I/O and register placement.

All registered macrocells share common clock and output enable control pins. Any macrocell can be configured as registered or I/O. Up to eight registers or up to eight I/Os are possible in this mode.

Dedicated input or output functions can be implemented as subsets of the I/O function.

Registered outputs have eight product terms per output. I/Os have seven product terms per output.

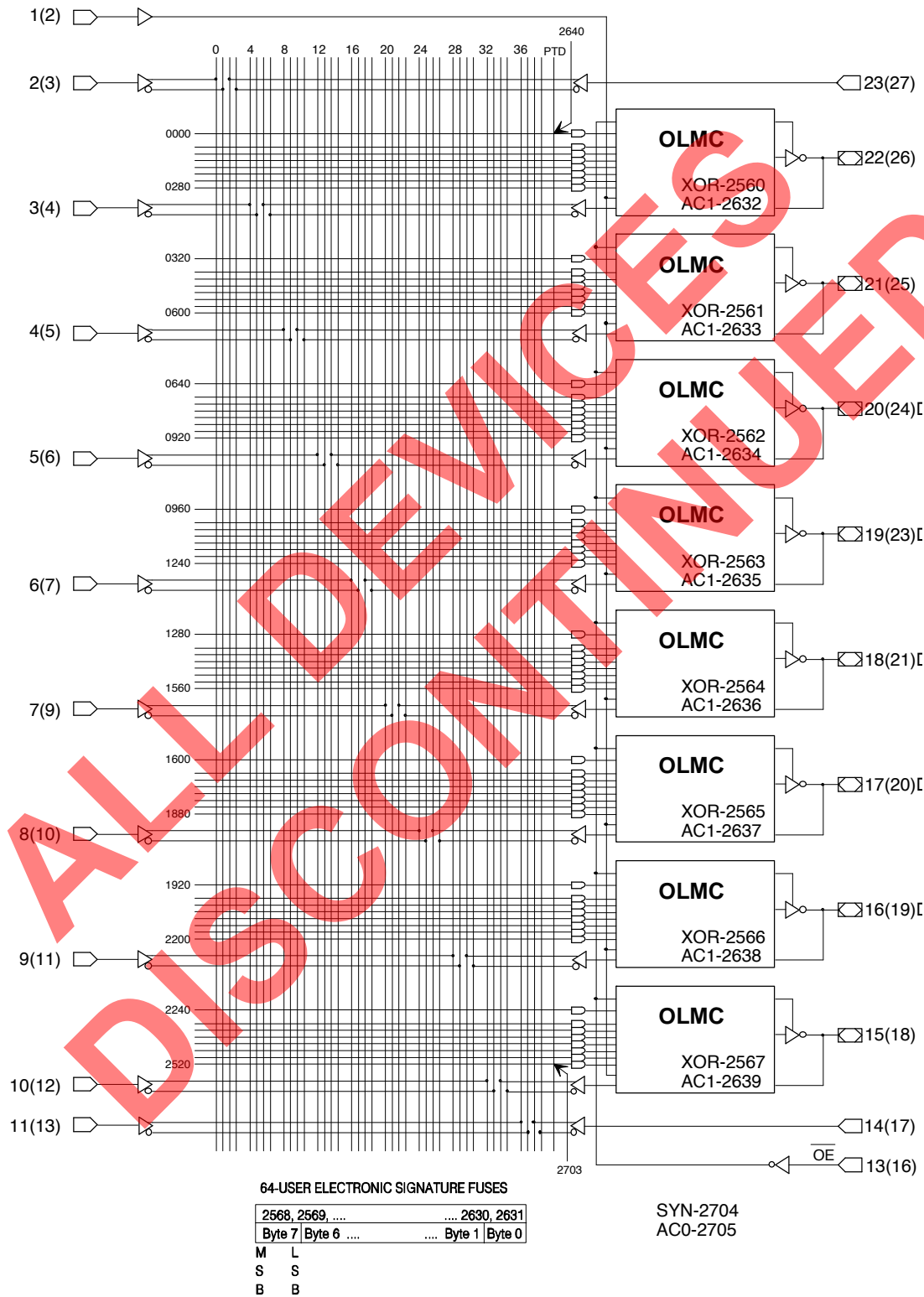
The JEDEC fuse numbers, including the User Electronic Signature (UES) fuses and the Product Term Disable (PTD) fuses, are shown on the logic diagram on the following page.



Note: The development software configures all of the architecture control bits and checks for proper pin usage automatically.

**Registered Mode Logic Diagram**

**DIP (PLCC) Package Pinouts**



## Complex Mode

In the Complex mode, macrocells are configured as output only or I/O functions.

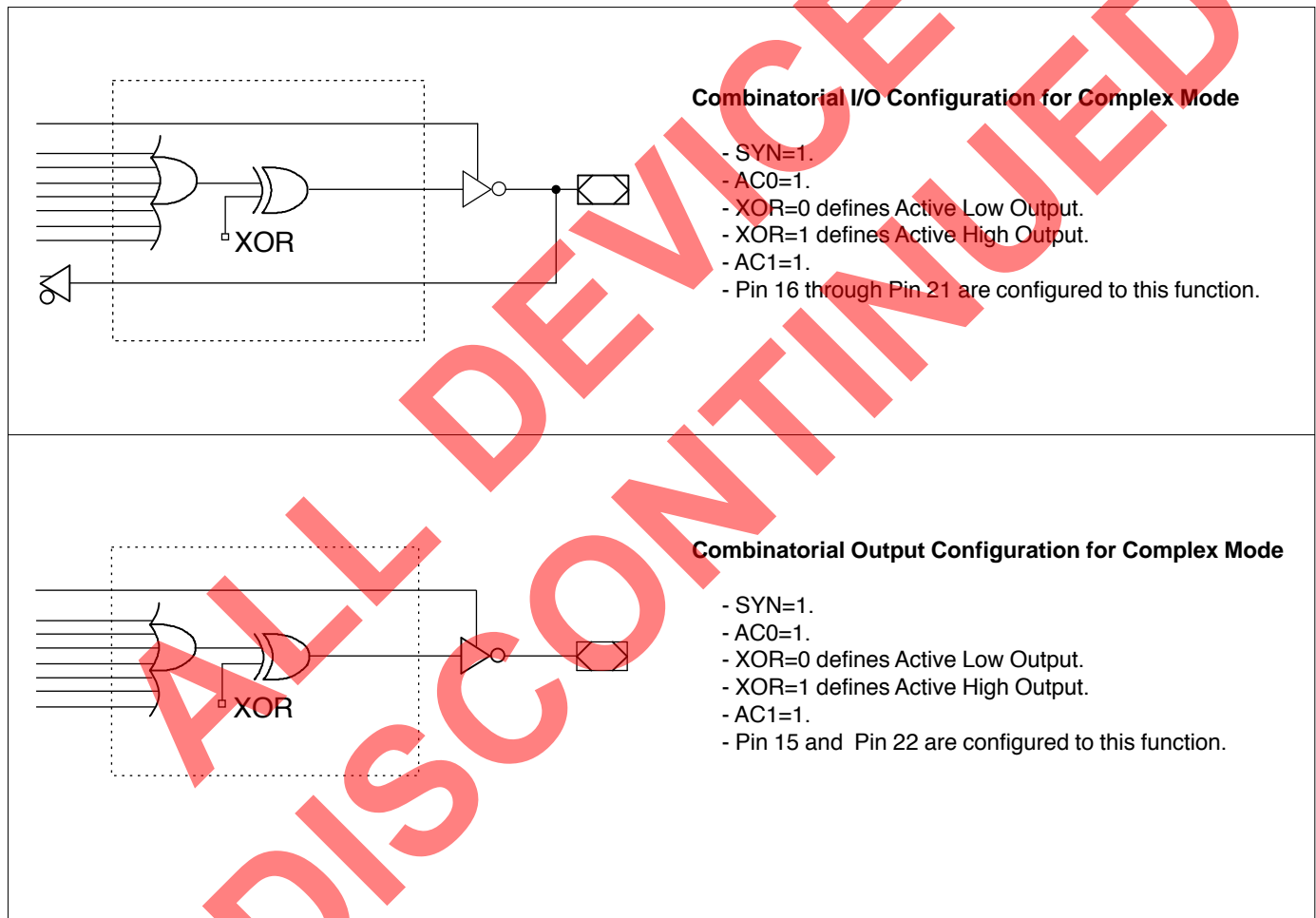
Architecture configurations available in this mode are similar to the common 20L8 and 20P8 devices with programmable polarity in each macrocell.

Up to six I/Os are possible in this mode. Dedicated inputs or outputs can be implemented as subsets of the I/O function. The two outer most macrocells (pins 15 & 22) do not have input capability. De-

signs requiring eight I/Os can be implemented in the Registered mode.

All macrocells have seven product terms per output. One product term is used for programmable output enable control. Pins 1 and 13 are always available as data inputs into the AND array.

The JEDEC fuse numbers including the UES fuses and PTD fuses are shown on the logic diagram on the following page.

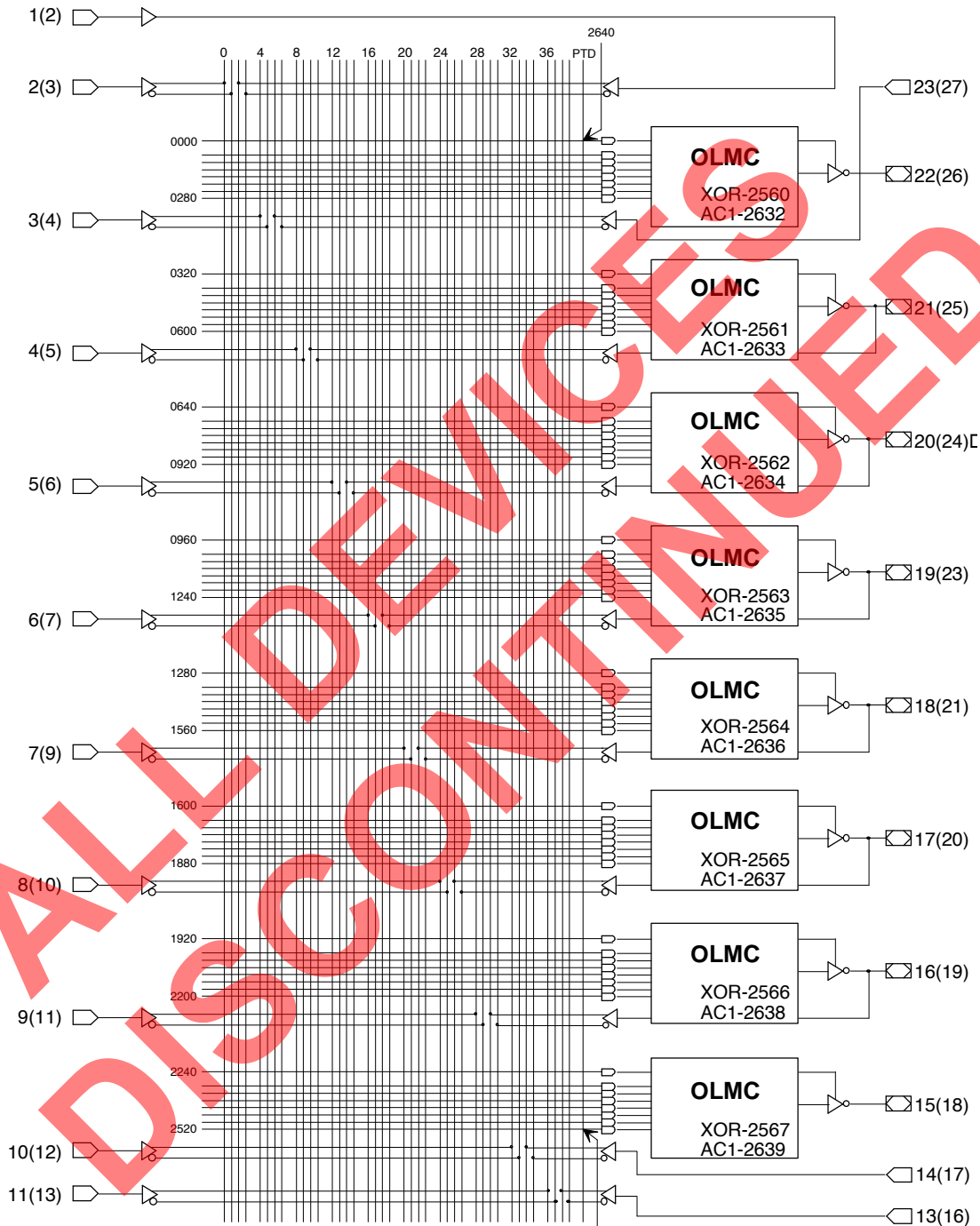


Note: The development software configures all of the architecture control bits and checks for proper pin usage automatically.



**Complex Mode Logic Diagram**

**DIP (PLCC) Package Pinouts**



**64-USER ELECTRONIC SIGNATURE FUSES**

2568, 2569, ....	.... 2630, 2631
Byte 7 Byte 6 ....	.... Byte 1 Byte 0

M L  
S S  
B B

SYN-2704  
AC0-2705

## Simple Mode

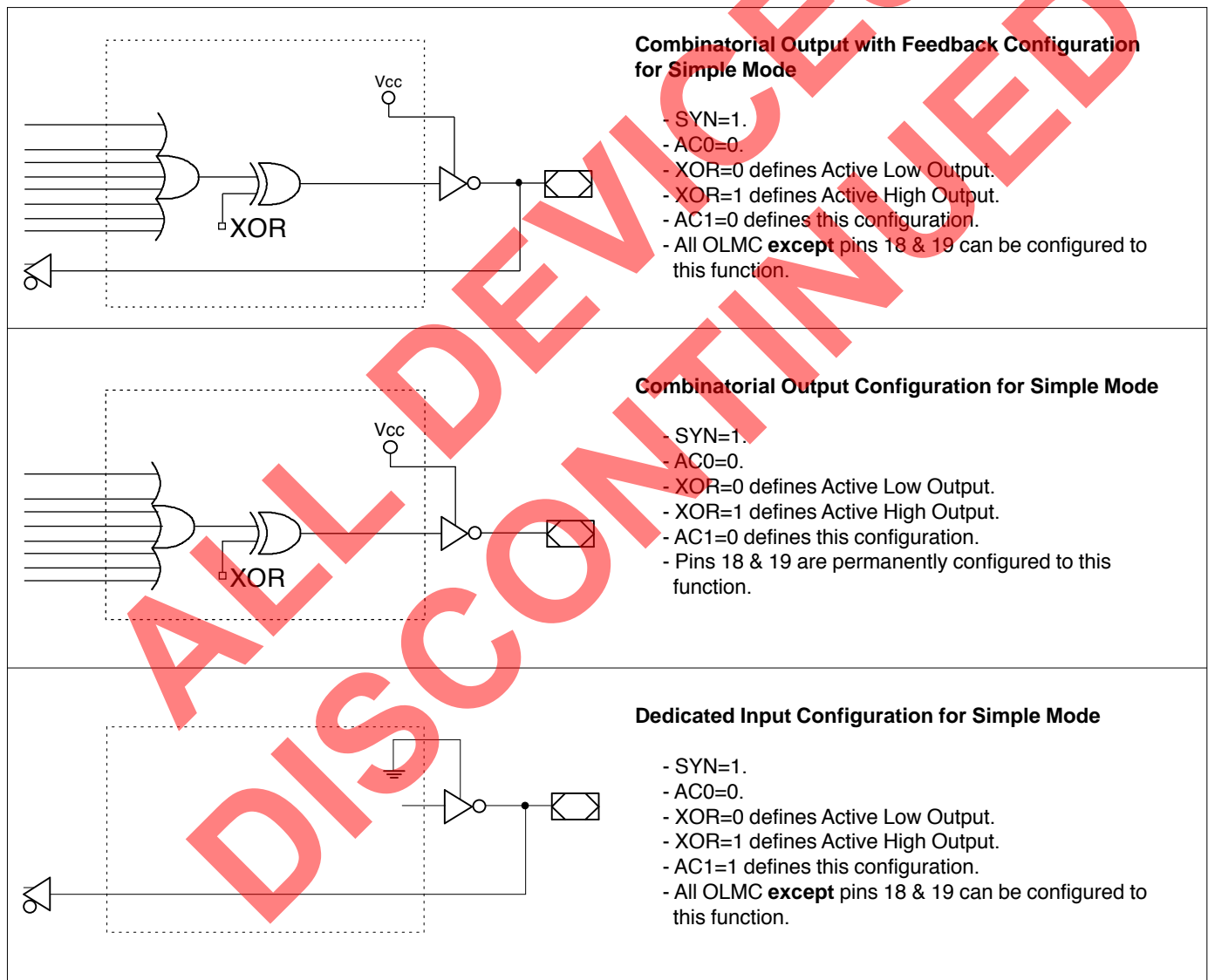
In the Simple mode, pins are configured as dedicated inputs or as dedicated, always active, combinatorial outputs.

Architecture configurations available in this mode are similar to the common 14L8 and 16P6 devices with many permutations of generic output polarity or input choices.

All outputs in the simple mode have a maximum of eight product terms that can control the logic. In addition, each output has programmable polarity.

Pins 1 and 13 are always available as data inputs into the AND array. The "center" two macrocells (pins 18 and 19) cannot be used in the input configuration.

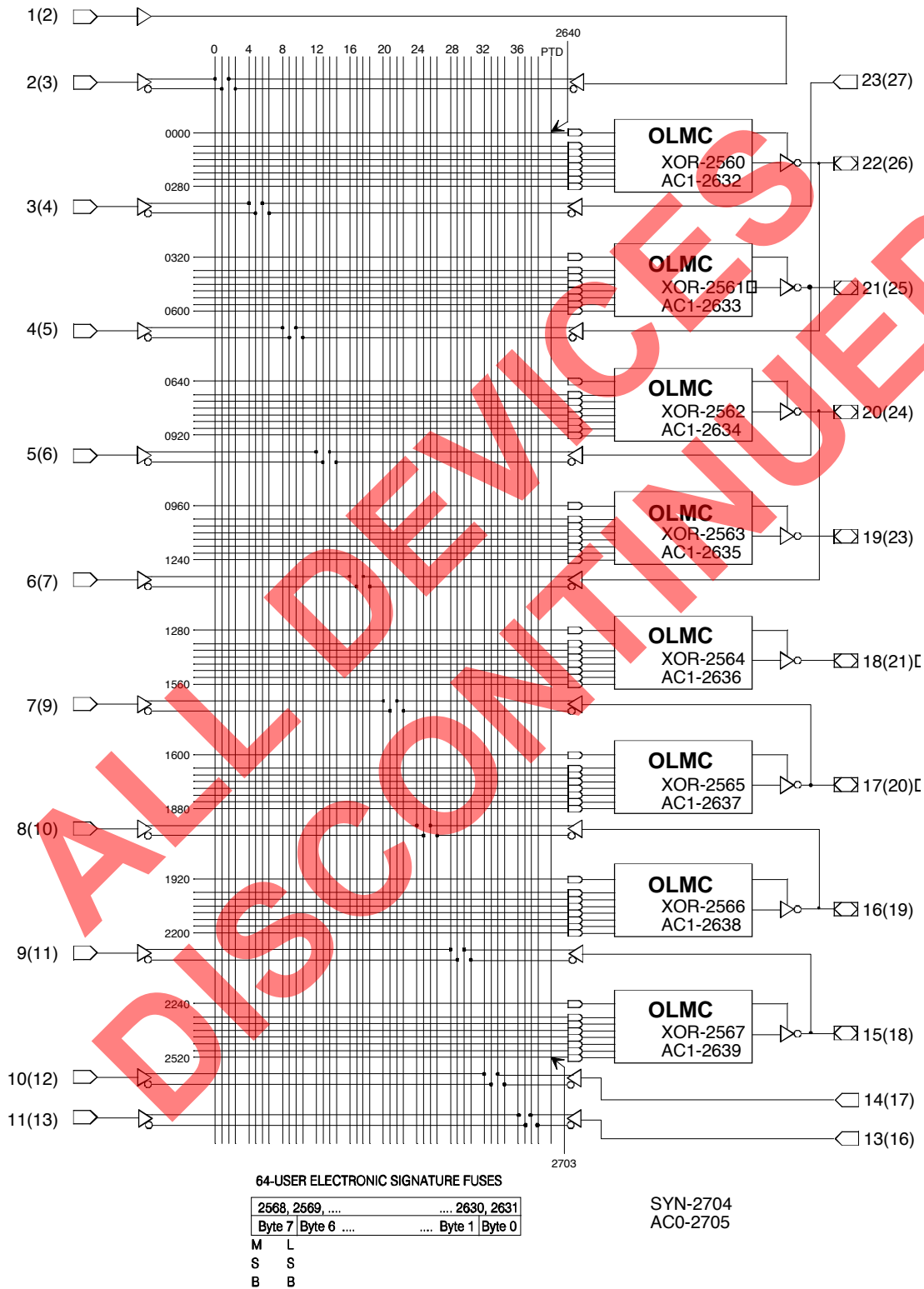
The JEDEC fuse numbers including the UES fuses and PTD fuses are shown on the logic diagram on the following page.



Note: The development software configures all of the architecture control bits and checks for proper pin usage automatically.

**Simple Mode Logic Diagram**

**DIP (PLCC) Package Pinouts**



## Absolute Maximum Ratings<sup>(1)</sup>

Supply voltage  $V_{CC}$  ..... -0.5 to +7V  
 Input voltage applied ..... -2.5 to  $V_{CC} + 1.0V$   
 Off-state output voltage applied ..... -2.5 to  $V_{CC} + 1.0V$   
 Storage Temperature ..... -65 to 150°C  
 Ambient Temperature with

Power Applied ..... -55 to 125°C

1. Stresses above those listed under the "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress only ratings and functional operation of the device at these or at any other conditions above those indicated in the operational sections of this specification is not implied (while programming, follow the programming specifications).

## Recommended Operating Conditions

### Commercial Devices:

Ambient Temperature ( $T_A$ ) ..... 0 to 75°C  
 Supply voltage ( $V_{CC}$ )  
 with Respect to Ground ..... +4.75 to +5.25V

### Industrial Devices:

Ambient Temperature ( $T_A$ ) ..... -40 to 85°C  
 Supply voltage ( $V_{CC}$ )  
 with Respect to Ground ..... +4.50 to +5.50V

## DC Electrical Characteristics

Over Recommended Operating Conditions (Unless Otherwise Specified)

SYMBOL	PARAMETER	CONDITION	MIN.	TYP. <sup>3</sup>	MAX.	UNITS
$V_{IL}$	Input Low Voltage		$V_{SS} - 0.5$	—	0.8	V
$V_{IH}$	Input High Voltage		2.0	—	$V_{CC} + 1$	V
$I_{IL}^1$	Input or I/O Low Leakage Current	$0V \leq V_{IN} \leq V_{IL} (MAX.)$	—	—	-100	$\mu A$
$I_{IH}$	Input or I/O High Leakage Current	$3.5V \leq V_{IN} \leq V_{CC}$	—	—	10	$\mu A$
$V_{OL}$	Output Low Voltage	$I_{OL} = MAX.$ $V_{IN} = V_{IL}$ or $V_{IH}$	—	—	0.5	V
$V_{OH}$	Output High Voltage	$I_{OH} = MAX.$ $V_{IN} = V_{IL}$ or $V_{IH}$	2.4	—	—	V
$I_{OL}$	Low Level Output Current		—	—	16	mA
$I_{OH}$	High Level Output Current		—	—	-3.2	mA
$I_{OS}^2$	Output Short Circuit Current	$V_{CC} = 5V$ $V_{OUT} = 0.5V$ $T_A = 25^\circ C$	-30	—	-150	mA

### COMMERCIAL

$I_{CC}$	Operating Power Supply Current	$V_{IL} = 0.5V$ $V_{IH} = 3.0V$ $f_{toggle} = 15MHz$ Outputs Open	L -5/-7/-10	—	75	115	mA
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### INDUSTRIAL

$I_{CC}$	Operating Power Supply Current	$V_{IL} = 0.5V$ $V_{IH} = 3.0V$ $f_{toggle} = 15MHz$ Outputs Open	L-10	—	75	130	mA
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1) The leakage current is due to the internal pull-up resistor on all pins. See **Input Buffer** section for more information.

2) One output at a time for a maximum duration of one second.  $V_{out} = 0.5V$  was selected to avoid test problems caused by tester ground degradation. Characterized but not 100% tested.

3) Typical values are at  $V_{CC} = 5V$  and  $T_A = 25^\circ C$

## AC Switching Characteristics

Over Recommended Operating Conditions

				COM		COM		COM/IND		
PARAMETER	TEST COND <sup>1</sup> .	DESCRIPTION		-5		-7		-10		UNITS
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
<b>t<sub>pd</sub></b>	A	Input or I/O to	8 outputs switching	1	5	3	7.5	3	10	ns
		Comb. Output	1 output switching	—	—	—	7	—	—	ns
<b>t<sub>co</sub></b>	A	Clock to Output Delay		1	4	2	5	2	7	ns
<b>t<sub>cf</sub><sup>2</sup></b>	—	Clock to Feedback Delay		—	3	—	3	—	6	ns
<b>t<sub>su</sub></b>	—	Setup Time, Input or Feedback before Clock↑		3	—	5	—	7.5	—	ns
<b>t<sub>h</sub></b>	—	Hold Time, Input or Feedback after Clock↑		0	—	0	—	0	—	ns
<b>f<sub>max</sub><sup>3</sup></b>	A	Maximum Clock Frequency with External Feedback, 1/(t <sub>su</sub> + t <sub>co</sub> )		142.8	—	100	—	66.7	—	MHz
	A	Maximum Clock Frequency with Internal Feedback, 1/(t <sub>su</sub> + t <sub>cf</sub> )		166	—	125	—	71.4	—	MHz
	A	Maximum Clock Frequency with No Feedback		166	—	125	—	83.3	—	MHz
<b>t<sub>wh</sub></b>	—	Clock Pulse Duration, High		3	—	4	—	6	—	ns
<b>t<sub>wl</sub></b>	—	Clock Pulse Duration, Low		3	—	4	—	6	—	ns
<b>t<sub>en</sub></b>	B	Input or I/O to Output Enabled		1	6	3	9	3	10	ns
	B	OE to Output Enabled		1	6	2	6	2	10	ns
<b>t<sub>dis</sub></b>	C	Input or I/O to Output Disabled		1	5	2	9	2	10	ns
	C	OE to Output Disabled		1	5	1.5	6	1.5	10	ns

1) Refer to **Switching Test Conditions** section.

2) Calculated from f<sub>max</sub> with internal feedback. Refer to **f<sub>max</sub> Descriptions** section.

3) Refer to **f<sub>max</sub> Descriptions** section. Characterized initially and after any design or process changes that may affect these parameters.

## Capacitance (T<sub>A</sub> = 25°C, f = 1.0 MHz)

SYMBOL	PARAMETER	MAXIMUM*	UNITS	TEST CONDITIONS
C <sub>I</sub>	Input Capacitance	8	pF	V <sub>CC</sub> = 5.0V, V <sub>I</sub> = 2.0V
C <sub>I/O</sub>	I/O Capacitance	8	pF	V <sub>CC</sub> = 5.0V, V <sub>I/O</sub> = 2.0V

\*Characterized but not 100% tested

## Absolute Maximum Ratings<sup>(1)</sup>

Supply voltage  $V_{CC}$  ..... -0.5 to +7V  
 Input voltage applied ..... -2.5 to  $V_{CC} + 1.0V$   
 Off-state output voltage applied ..... -2.5 to  $V_{CC} + 1.0V$   
 Storage Temperature ..... -65 to 150°C  
 Ambient Temperature with

Power Applied ..... -55 to 125°C

1. Stresses above those listed under the "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress only ratings and functional operation of the device at these or at any other conditions above those indicated in the operational sections of this specification is not implied (while programming, follow the programming specifications).

## Recommended Operating Conditions

### Commercial Devices:

Ambient Temperature ( $T_A$ ) ..... 0 to 75°C

Supply voltage ( $V_{CC}$ )

with Respect to Ground ..... +4.75 to +5.25V

### Industrial Devices:

Ambient Temperature ( $T_A$ ) ..... -40 to 85°C

Supply voltage ( $V_{CC}$ )

with Respect to Ground ..... +4.50 to +5.50V

## DC Electrical Characteristics

Over Recommended Operating Conditions (Unless Otherwise Specified)

SYMBOL	PARAMETER	CONDITION	MIN.	TYP. <sup>3</sup>	MAX.	UNITS
<b>V<sub>IL</sub></b>	Input Low Voltage		$V_{SS} - 0.5$	—	0.8	V
<b>V<sub>IH</sub></b>	Input High Voltage		2.0	—	$V_{CC} + 1$	V
<b>I<sub>IL</sub><sup>1</sup></b>	Input or I/O Low Leakage Current	$0V \leq V_{IN} \leq V_{IL} (MAX.)$	—	—	-100	μA
<b>I<sub>IH</sub></b>	Input or I/O High Leakage Current	$3.5V \leq V_{IN} \leq V_{CC}$	—	—	10	μA
<b>V<sub>OL</sub></b>	Output Low Voltage	$I_{OL} = MAX.$ $V_{IN} = V_{IL}$ or $V_{IH}$	—	—	0.5	V
<b>V<sub>OH</sub></b>	Output High Voltage	$I_{OH} = MAX.$ $V_{IN} = V_{IL}$ or $V_{IH}$	2.4	—	—	V
<b>I<sub>OL</sub></b>	Low Level Output Current		—	—	24	mA
<b>I<sub>OH</sub></b>	High Level Output Current		—	—	-3.2	mA
<b>I<sub>OS</sub><sup>2</sup></b>	Output Short Circuit Current	$V_{CC} = 5V$ $V_{OUT} = 0.5V$ $T_A = 25^\circ C$	-30	—	-150	mA

### COMMERCIAL

<b>I<sub>CC</sub></b>	Operating Power Supply Current	$V_{IL} = 0.5V$ $V_{IH} = 3.0V$ $f_{toggle} = 15MHz$ Outputs Open	<b>L</b> -7/-10	—	75	115	mA
			<b>L</b> -15/-25	—	75	90	mA
			<b>Q</b> -15/-25	—	45	55	mA

### INDUSTRIAL

<b>I<sub>CC</sub></b>	Operating Power Supply Current	$V_{IL} = 0.5V$ $V_{IH} = 3.0V$ $f_{toggle} = 15MHz$ Outputs Open	<b>L</b> -10/-15/-25	—	75	130	mA
			<b>Q</b> -20/-25	—	45	65	mA

1) The leakage current is due to the internal pull-up resistor on all pins. See **Input Buffer** section for more information.

2) One output at a time for a maximum duration of one second.  $V_{out} = 0.5V$  was selected to avoid test problems caused by tester ground degradation. Characterized but not 100% tested.

3) Typical values are at  $V_{CC} = 5V$  and  $T_A = 25^\circ C$

## AC Switching Characteristics

Over Recommended Operating Conditions

				COM		COM / IND		COM / IND		IND		COM / IND		
PARAM.	TEST COND <sup>1</sup> .	DESCRIPTION		-7		-10		-15		-20		-25		UNITS
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
<b>t<sub>pd</sub></b>	A	Input or I/O to Comb. Output	8 outputs switching	3	7.5	3	10	3	15	3	20	3	25	ns
			1 output switching	—	7	—	—	—	—	—	—	—	—	ns
<b>t<sub>co</sub></b>	A	Clock to Output Delay		2	5	2	7	2	10	2	11	2	12	ns
<b>t<sub>cf</sub><sup>2</sup></b>	—	Clock to Feedback Delay		—	3	—	6	—	8	—	9	—	10	ns
<b>t<sub>su</sub></b>	—	Setup Time, Input or Fdbk before Clk↑		7	—	10	—	12	—	13	—	15	—	ns
<b>t<sub>h</sub></b>	—	Hold Time, Input or Fdbk after Clk↑		0	—	0	—	0	—	0	—	0	—	ns
<b>f<sub>max</sub><sup>3</sup></b>	A	Maximum Clock Frequency with External Feedback, 1/(t <sub>su</sub> + t <sub>co</sub> )		83.3	—	58.8	—	45.5	—	41.6	—	37	—	MHz
	A	Maximum Clock Frequency with Internal Feedback, 1/(t <sub>su</sub> + t <sub>cf</sub> )		100	—	62.5	—	50	—	45.4	—	40	—	MHz
	A	Maximum Clock Frequency with No Feedback		100	—	62.5	—	62.5	—	50	—	41.7	—	MHz
<b>t<sub>wh</sub></b>	—	Clock Pulse Duration, High		5	—	8	—	8	—	10	—	12	—	ns
<b>t<sub>wl</sub></b>	—	Clock Pulse Duration, Low		5	—	8	—	8	—	10	—	12	—	ns
<b>t<sub>en</sub></b>	B	Input or I/O to Output Enabled		3	9	3	10	—	15	—	18	—	25	ns
	B	$\overline{\text{OE}}$ to Output Enabled		2	6	2	10	—	15	—	18	—	20	ns
<b>t<sub>dis</sub></b>	C	Input or I/O to Output Disabled		2	9	2	10	—	15	—	18	—	25	ns
	C	$\overline{\text{OE}}$ to Output Disabled		1.5	6	1.5	10	—	15	—	18	—	20	ns

1) Refer to **Switching Test Conditions** section.

2) Calculated from f<sub>max</sub> with internal feedback. Refer to **f<sub>max</sub> Descriptions** section.

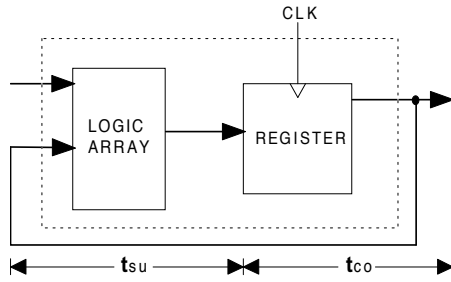
3) Refer to **f<sub>max</sub> Descriptions** section.

## Capacitance (T<sub>A</sub> = 25°C, f = 1.0 MHz)

SYMBOL	PARAMETER	MAXIMUM*	UNITS	TEST CONDITIONS
C <sub>I</sub>	Input Capacitance	8	pF	V <sub>CC</sub> = 5.0V, V <sub>I</sub> = 2.0V
C <sub>I/O</sub>	I/O Capacitance	8	pF	V <sub>CC</sub> = 5.0V, V <sub>I/O</sub> = 2.0V

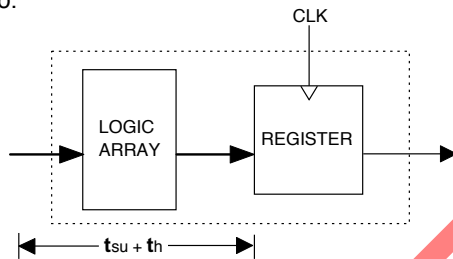
\*Characterized but not 100% tested.

## fmax Descriptions



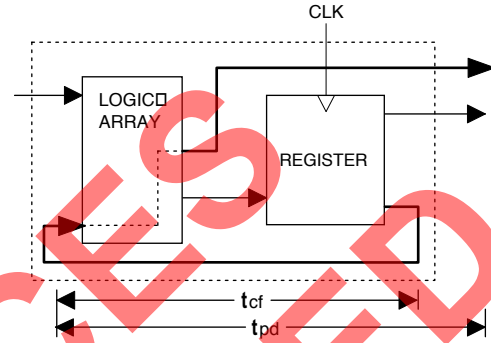
**fmax with External Feedback  $1/(t_{su}+t_{co})$**

**Note:** fmax with external feedback is calculated from measured tsu and tco.



**fmax with No Feedback**

**Note:** fmax with no feedback may be less than  $1/(t_{wh} + t_{wl})$ . This is to allow for a clock duty cycle of other than 50%.



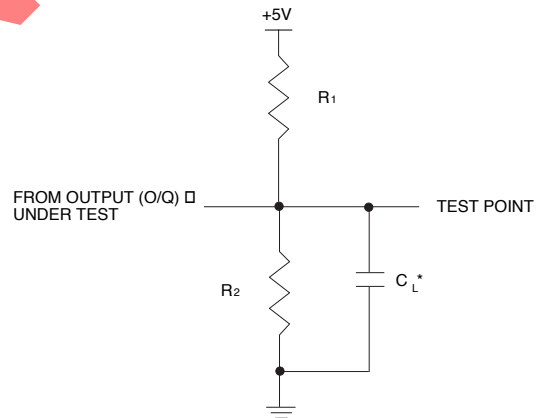
**fmax with Internal Feedback  $1/(t_{su}+t_{cf})$**

**Note:** tcf is a calculated value, derived by subtracting tsu from the period of fmax w/internal feedback ( $t_{cf} = 1/f_{max} - t_{su}$ ). The value of tcf is used primarily when calculating the delay from clocking a register to a combinational output (through registered feedback), as shown above. For example, the timing from clock to a combinational output is equal to  $t_{cf} + t_{pd}$ .

## Switching Test Conditions

Input Pulse Levels		GND to 3.0V
Input Rise and Fall Times	GAL20V8B	2 – 3ns 10% – 90%
	GAL20V8C	1.5ns 10% – 90%
Input Timing Reference Levels		1.5V
Output Timing Reference Levels		1.5V
Output Load		See Figure

3-state levels are measured 0.5V from steady-state active level.



\*CL INCLUDES TEST FIXTURE AND PROBE CAPACITANCE

### GAL20V8B Output Load Conditions (see figure)

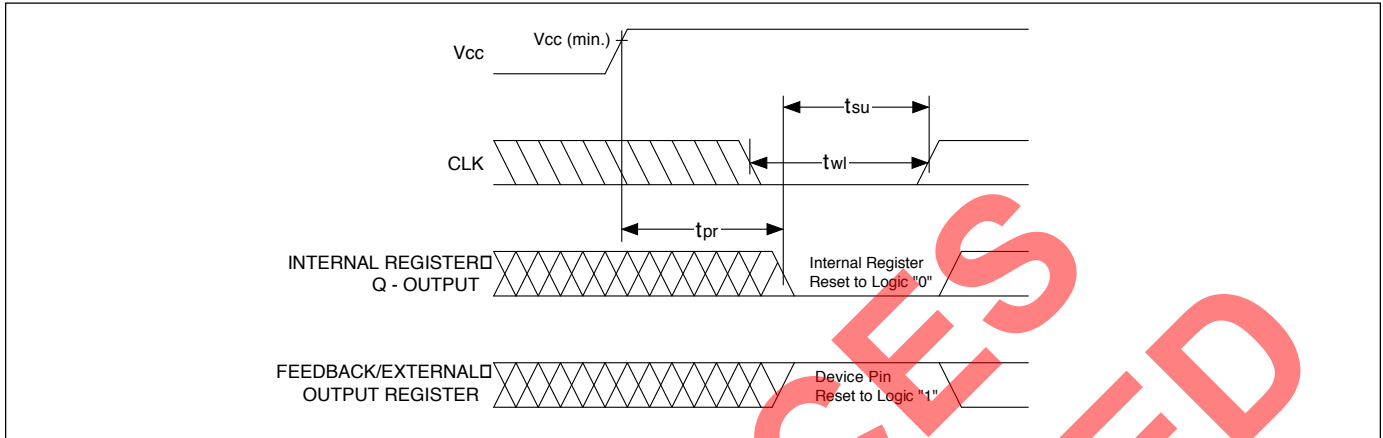
Test Condition		R1	R2	CL
A		200Ω	390Ω	50pF
B	Active High	∞	390Ω	50pF
	Active Low	200Ω	390Ω	50pF
C	Active High	∞	390Ω	5pF
	Active Low	200Ω	390Ω	5pF

### GAL20V8C Output Load Conditions (see figure)

Test Condition		R1	R2	CL
A		200Ω	200Ω	50pF
B	Active High	∞	200Ω	50pF
	Active Low	200Ω	200Ω	50pF
C	Active High	∞	200Ω	5pF
	Active Low	200Ω	200Ω	5pF



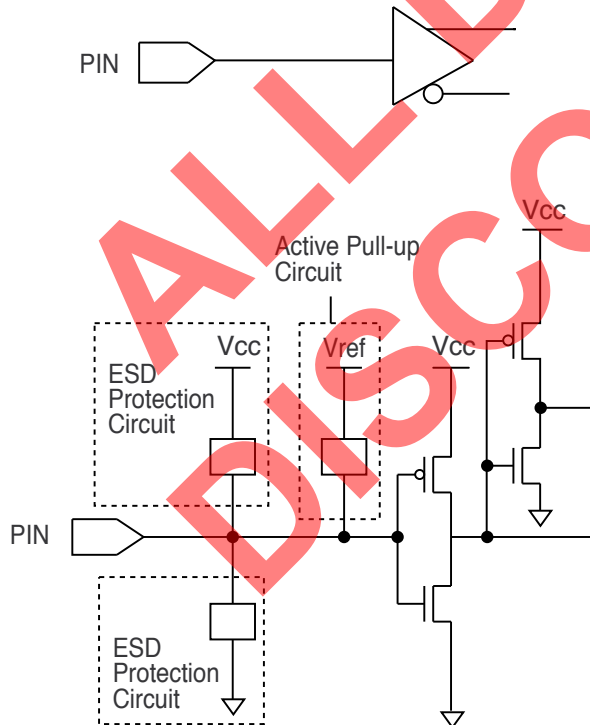
## Power-Up Reset



Circuitry within the GAL20V8 provides a reset signal to all registers during power-up. All internal registers will have their Q outputs set low after a specified time ( $t_{pr}$ , 1  $\mu$ s MAX). As a result, the state on the registered output pins (if they are enabled) will always be high on power-up, regardless of the programmed polarity of the output pins. This feature can greatly simplify state machine design by providing a known state on power-up. Because of the asynchronous nature of system power-up, some conditions must be met to provide

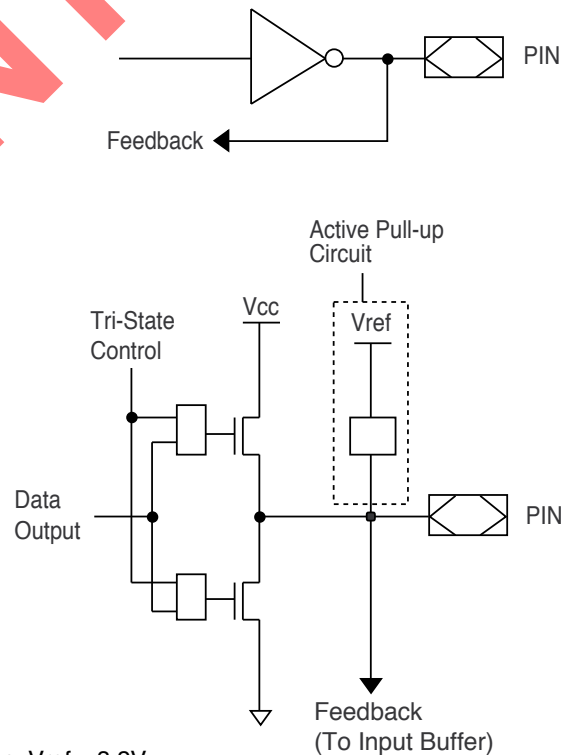
a valid power-up reset of the device. First, the  $V_{CC}$  rise must be monotonic. Second, the clock input must be at static TTL level as shown in the diagram during power up. The registers will reset within a maximum of  $t_{pr}$  time. As in normal system operation, avoid clocking the device until all input and feedback path setup times have been met. The clock must also meet the minimum pulse width requirements.

## Input/Output Equivalent Schematics



Typ.  $V_{ref} = 3.2V$

**Typical Input**

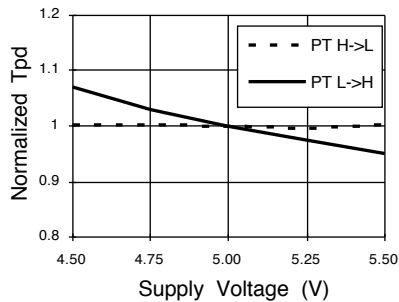


Typ.  $V_{ref} = 3.2V$

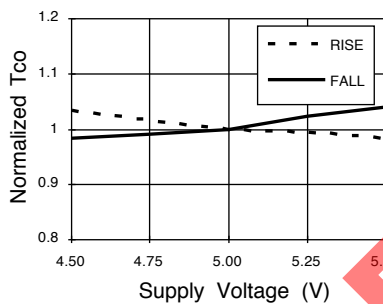
**Typical Output**

**GAL20V8C: Typical AC and DC Characteristic Diagrams**

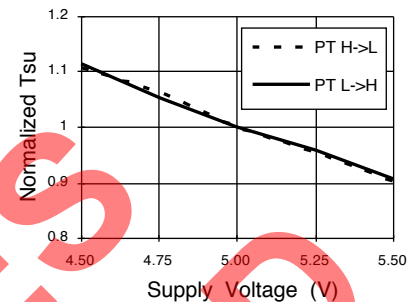
**Normalized Tpd vs Vcc**



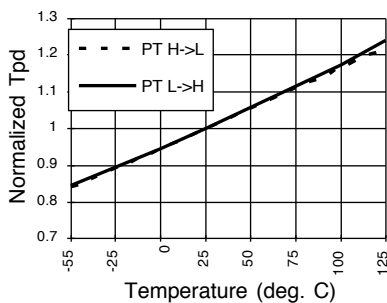
**Normalized Tco vs Vcc**



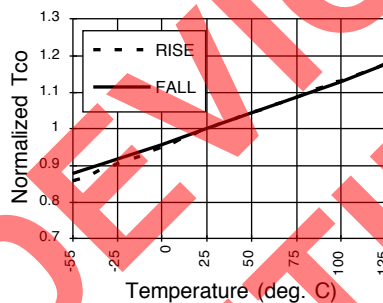
**Normalized Tsu vs Vcc**



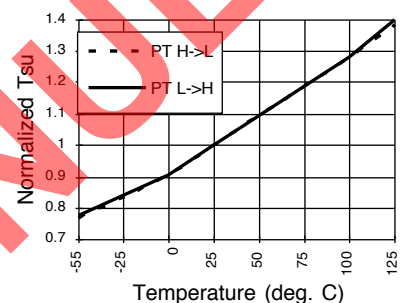
**Normalized Tpd vs Temp**



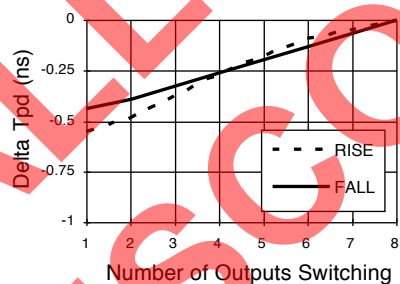
**Normalized Tco vs Temp**



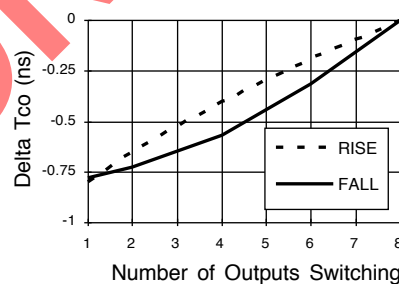
**Normalized Tsu vs Temp**



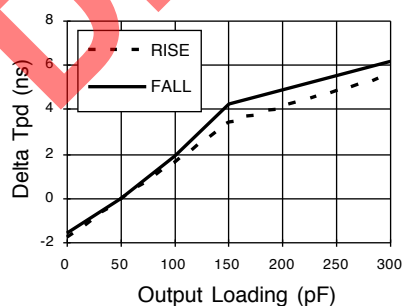
**Delta Tpd vs # of Outputs Switching**



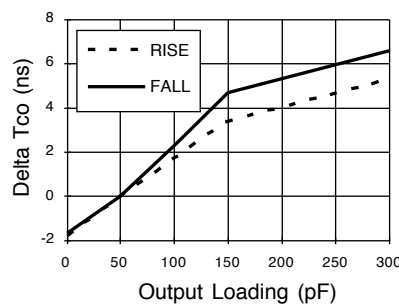
**Delta Tco vs # of Outputs Switching**



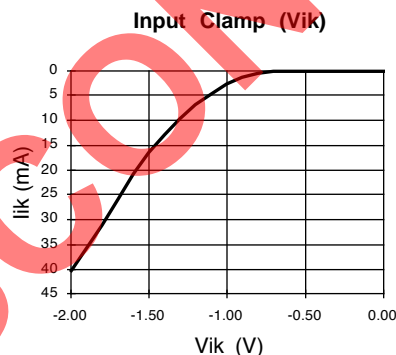
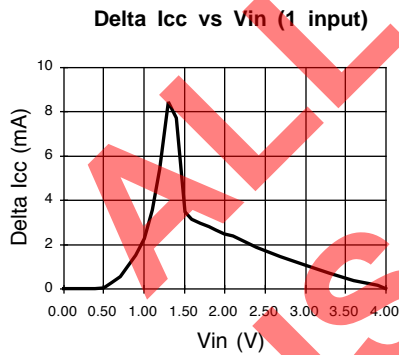
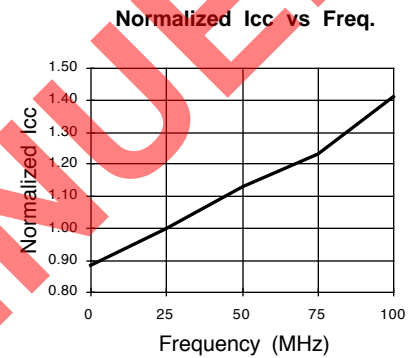
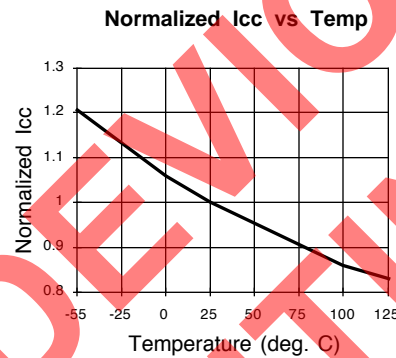
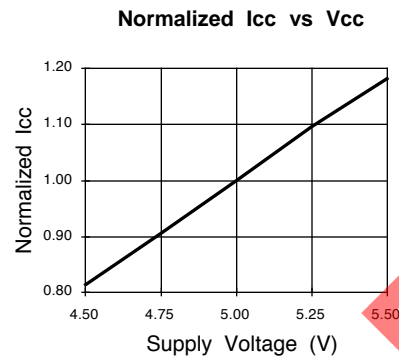
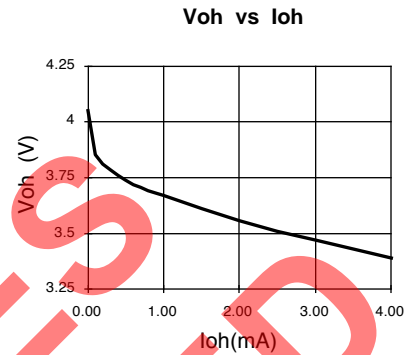
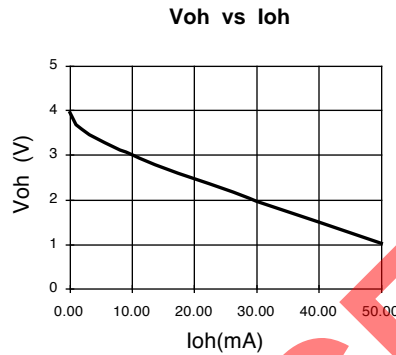
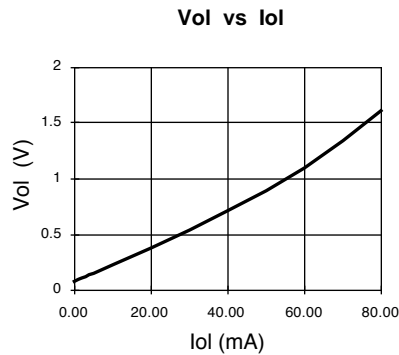
**Delta Tpd vs Output Loading**



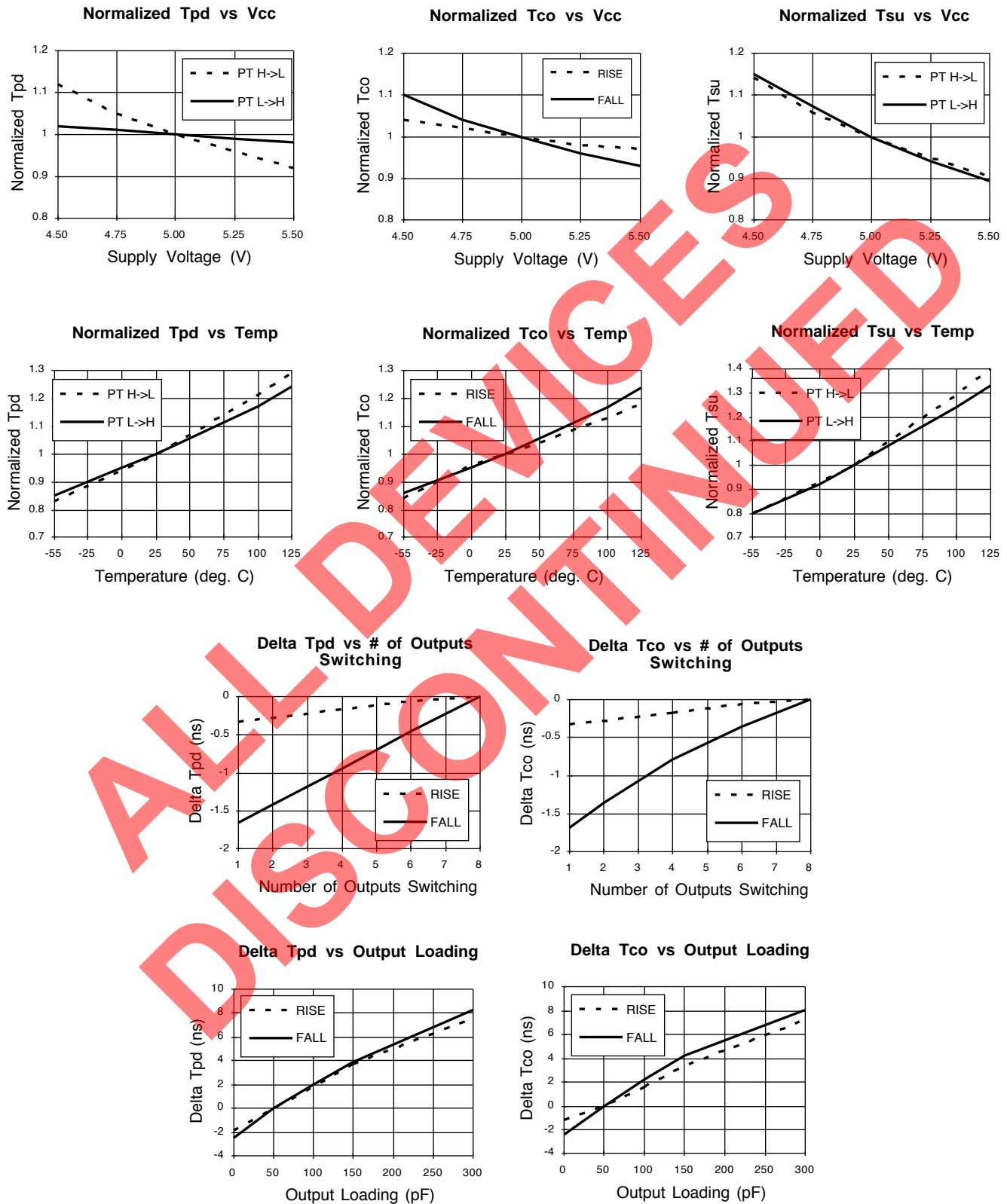
**Delta Tco vs Output Loading**



**GAL20V8C: Typical AC and DC Characteristic Diagrams**



**GAL20V8B-15/-25: Typical AC and DC Characteristic Diagrams**



**Revision History**

Date	Version	Change Summary
-	20v8_06	Previous Lattice release.
August 2006	20v8_07	Updated for lead-free package options.

ALL DEVICES  
DISCONTINUED